IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney Docket No. UCF-306DIV (which is a divisional of application SN: 10/082,658 filed 10/19/2001 which claims priority of SN: 09/881,620 filed June 14, 2001 and U. S. Provisional application 60/242,102 filed October 20, 2000)

Serial No.: 09/___,__ Filed: / /

Divisional Application of Serial No.: 10/082,658

Filed: 10/19/2001

First Named Inventor: Martin Richardson

For: EUV, XUV, AND X-RAY WAVELENGTH SOURCES CREATED FROM LASER PLASMA PRODUCED FROM LIQUID METAL SOLUTIONS,

AND NANO-SIZE PARTICLES IN SOLUTIONS

Examiner: COURTNEY D. THOMAS

Group: 2882

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner of Patents and Trademarks P O Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §§ 1.97 and 1.98, record is being made below in a form PTO-1449 of documents which the Patent Office may wish to consider in connection with examination of the above-identified patent application. It is respectfully requested that the cited documents be carefully considered by the Examiner and made of record in this case. As provided in § 1.97(g), no representation is made or intended that a thorough art search was made. As provided in 37 C.F.R. § 1.97(h), this Supplemental Information Disclosure Statement does not constitute an admission of any kind, and specifically is not an admission that the documents listed on the attached PCT-1449 are, or are considered to be, material to the patentability of the above-identified patent application, as defined in 37 C.F.R. § 1.56(b).

Copies of the cited references were previously submitted to the USPTO in the parent application No.: 10/082,658 filed 10/19/2001 and 09/881,620 filed June 14, 2001 and made of record. Applicants claim priority to said application under 35 U. S. C. §120. Accordingly, copies of those documents are not provided with this Statement pursuant to 37 CFR § 1.98(d).

It is respectfully requested that the cited documents be carefully considered by the Examiner and made of record in the case.

Respectfully submitted,

Brian S. Steinberger Law Offices of Brian S. Steinberger, P.A. PTO Registration No. 36,423 101 Brevard Avenue Cocoa, Florida (321) 633-5080 (321) 633-9322 Fax

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US DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

APPLICANT: MARTIN RICHARDSON

FOR: EUV, XUV, AND X-RAY WAVELENGTH SOURCES CREATED FROM LASER PLASM

PRODUCED FROM LIQUID METAL SOLUTIONS, AND NANO-SIZE PARTICLES IN SOLUTION

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Courtney Thomas 01.02.03

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